Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/600,637	HAYNER ET AL.
Examiner	Art Unit

Kim-Kwok CHU

2627

SEARCHED					
Class	Subclass	Date	Examiner		
369	44.26	12/1/2006	кс		
369	44.29	12/1/2006	кс		
369	53.28	12/1/2006	кс		
369	53.35	12/1/2006	кс		
369	44.27	12/1/2006	кс		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

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SEARCH (INCLUDING SEAR	NOTES CH STRATEGY	()
	DATE	EXMR
East Search Updated	12/1/2006	кс